

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 09/884,180 | Applicant(s)/Patent Under Reexamination BONNEAU ET AL. | |
| | Examiner St. John Courtenay III | Art Unit 2126 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------------|----------------|
| * | A | US-6,055,515 | 04-2000 | Consentino et al. | 705/27 |
| * | B | US-5,812,135 | 09-1998 | Kotchey, Christopher Michael | 345/853 |
| * | C | US-5,740,425 | 04-1998 | Povilus, David S. | 707/100 |
| * | D | US-5,737,732 | 04-1998 | Gibson et al. | 707/2 |
| * | E | US-5,715,444 | 02-1998 | Danish et al. | 707/4 |
| * | F | US-5,701,137 | 12-1997 | Kiernan et al. | 345/853 |
| * | G | US-2003/0085931 | 05-2003 | Card et al. | 345/853 |
| * | H | US-6,154,750 A | 11-2000 | Roberge et al. | 707/104.1 |
| * | I | US-6,381,611 B1 | 04-2002 | Roberge et al. | 707/104.1 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.